

**C²MOS DIGITAL INTEGRATED CIRCUIT
SILICON MONOLITHIC**

TC40H375P/F

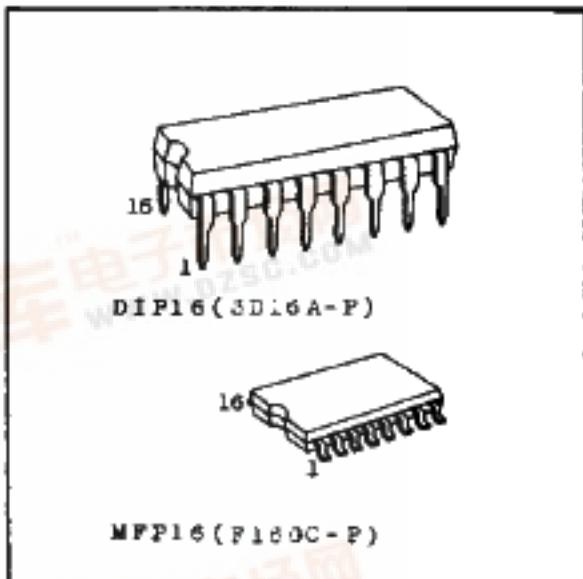
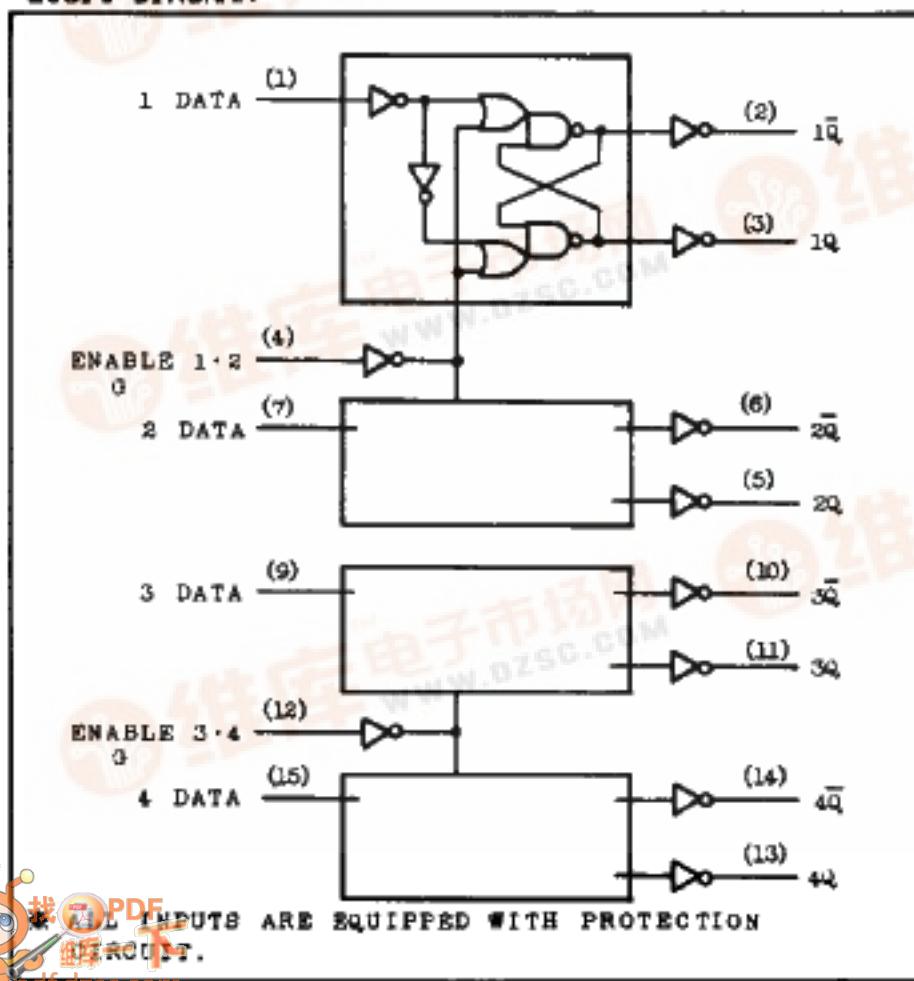
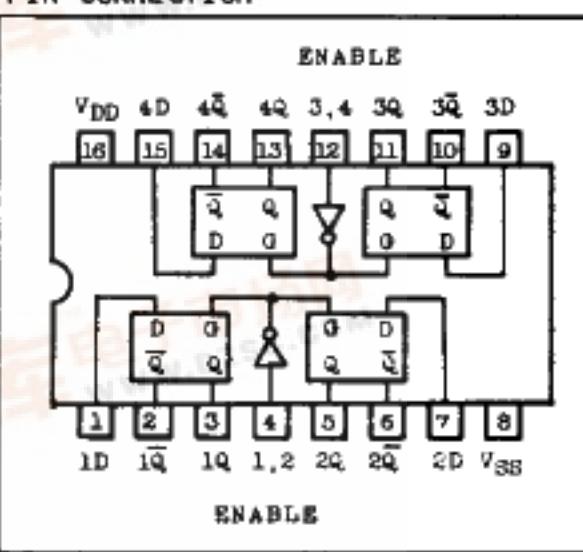
TC40H375 4-BIT BISTABLE LATCH

The TC40H375 is a 4-bit latch having ENABLE input terminal common in two circuits.

When ENABLE input is at "H" level, DATA input is transmitted to output as it is. If ENABLE input is transferred from "H" level to "L" level, latch holds input DATA immediately before falling. When ENABLE input is at "L" level, output does not change even if input DATA changes.

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V _{DD}	V _{SS} -0.5 ~ V _{SS} +10	V
Input Voltage	V _{IN}	V _{SS} -0.5 ~ V _{DD} +0.5	V
Output Voltage	V _{OUT}	V _{SS} -0.5 ~ V _{DD} +0.5	V
Input Current	I _{IN}	±10	mA
Power Dissipation	P _D	300(DIP)/180(MFP)	mW
Storage Temperature	T _{stg}	-65 ~ 150	°C
Lead Temp./Time	T _{sol}	260°C • 10 sec	

LOGIC DIAGRAM

PIN CONNECTION

TRUTH TABLE

INPUT		OUTPUT	
DATA	ENABLE	Q	Q̄
L	H	L	H
H	H	H	L
X	L	No Change	

X=Don't Care

TC40H375P/FRECOMMENDED OPERATING CONDITIONS ($V_{SS}=0.0V$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Supply Voltage	V_{DD}	-	2.0	-	8.0	V
Input Voltage	V_{IN}	-	0	-	V_{DD}	V
Operating Temperature	T_{opr}	-	-40	-	85	°C

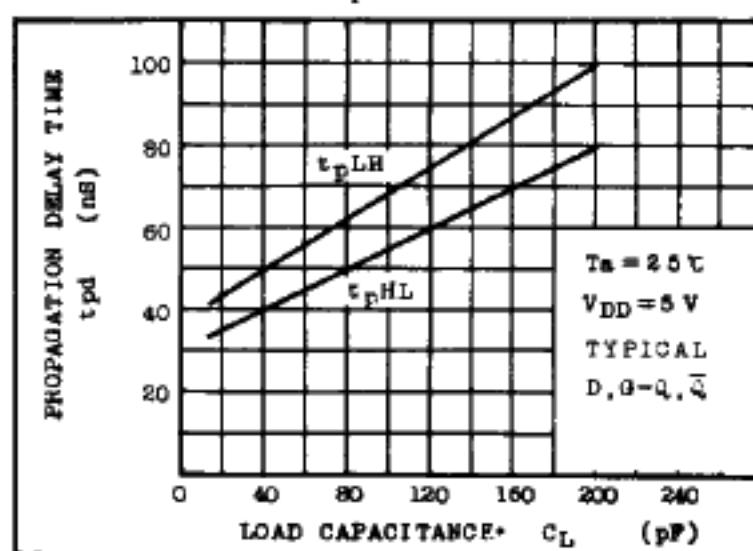
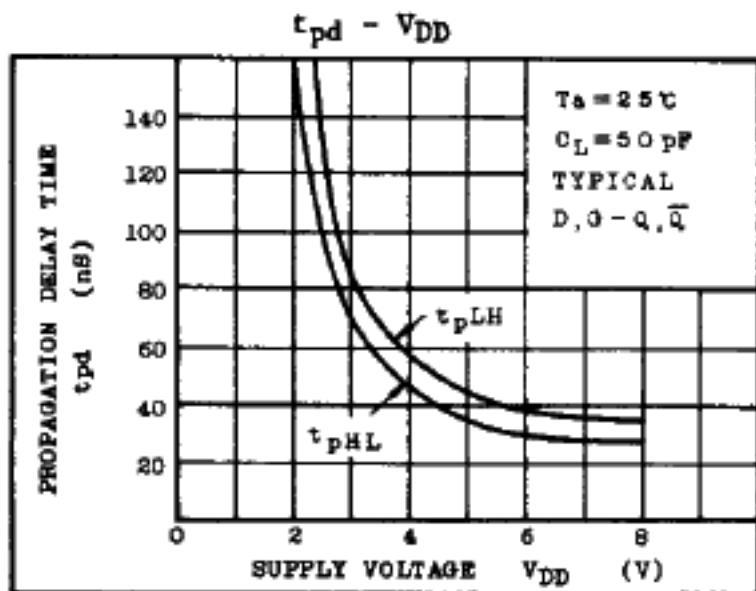
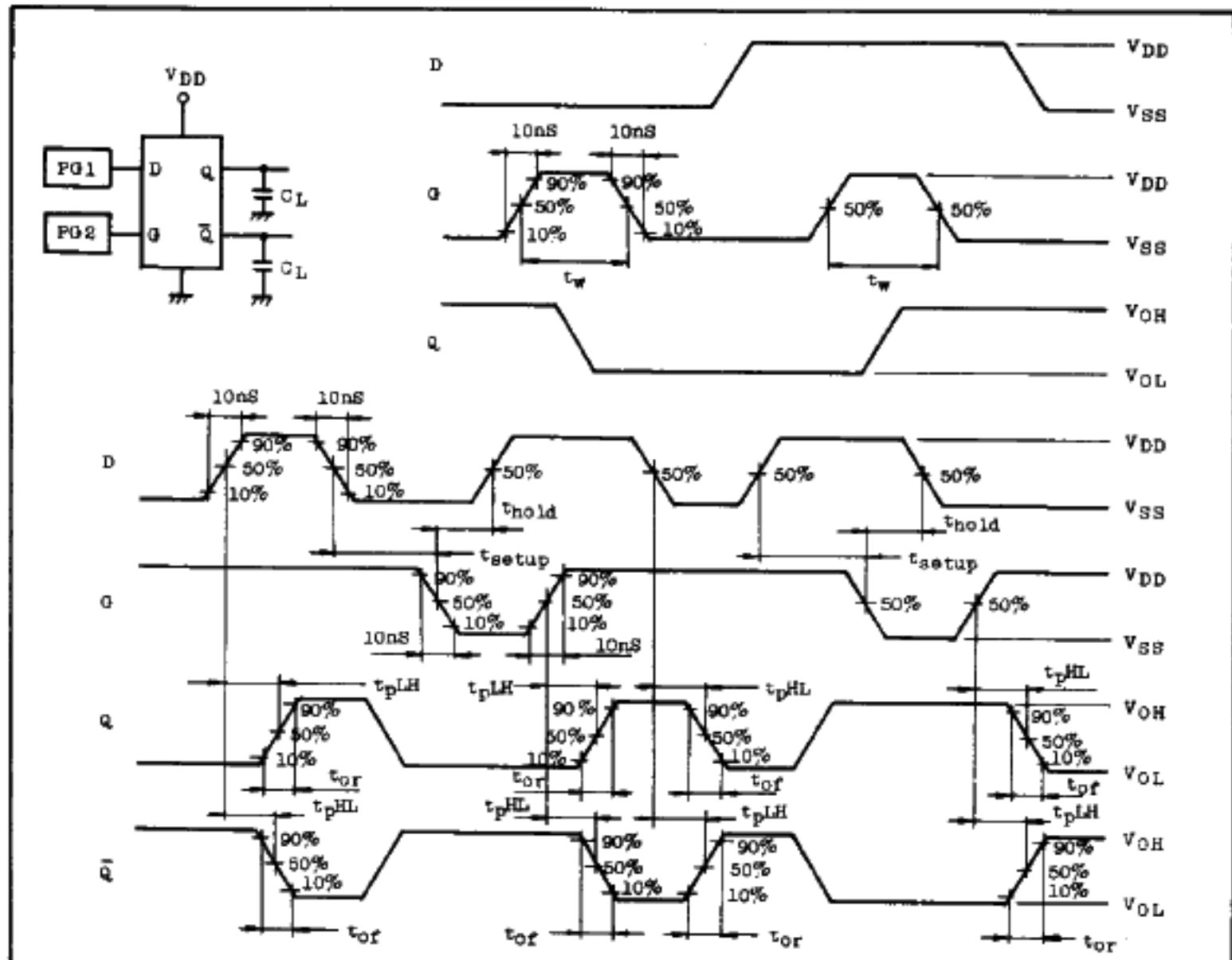
ELECTRICAL CHARACTERISTICS ($V_{SS}=0.0V$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	V_{DD} (V)	-40°C		25°C		85°C		UNIT		
				MIN.	MAX.	MIN.	TYP.	MAX.	MIN.			
High Level Output Voltage	V_{OH}	$ I_{OUT} < 1\mu A$ $V_{IN}=V_{SS}, V_{DD}$	5	4.95	-	4.95	5.0	-	4.95	-	V	
Low Level Output Voltage	V_{OL}	$ I_{OUT} < 1\mu A$ $V_{IN}=V_{SS}, V_{DD}$	5	-	0.05	-	0.0	0.05	-	0.05	V	
High Level Output Current	I_{OH}	$V_{OH}=4.6V$ $V_{IN}=V_{SS}, V_{DD}$	5	-0.52	-	-0.44	-	-	-0.36	-	mA	
Low Level Output Current	I_{OL}	$V_{OL}=0.4V$ $V_{IN}=V_{SS}, V_{DD}$	5	1.4	-	1.1	-	-	0.8	-	mA	
Input Voltage	High Level	V_{IH}	$ I_{OUT} < 1\mu A$ $V_{OUT}=0.5V$	5	4.0	-	4.0	-	-	4.0	-	V
	Low Level	V_{IL}	$V_{OUT}=4.5V$	5	-	1.0	-	-	1.0	-	1.0	V
Input "H" Level Current	I_{IH}	$V_{IH}=8.0V$	8	-	0.3	-	10^{-5}	0.3	-	1.0	μA	
Input "L" Level Current	I_{IL}	$V_{IL}=0.0V$	8	-	-0.3	-	-10^{-5}	-0.3	-	-1.0	μA	
Quiescent Supply Current	I_{DD}	* $V_{IN}=V_{SS}, V_{DD}$	5	-	12.5	-	10^{-3}	12.5	-	75	μA	

* All valid input combinations.

SWITCHING CHARACTERISTICS ($T_a=25^\circ C$, $V_{DD}=5V$, $C_L=15pF$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Output Rise Time	t_{or}		-	18	35	ns	
Output Fall Time	t_{of}		-	15	30	ns	
Propagation Delay Time	Low-High Level	t_{pLH}	DATA - Q, \bar{Q}	-	43	65	ns
	High-Low Level	t_{pHL}		-	35	53	
Propagation Delay Time	Low-High Level	t_{pLH}	ENABLE - Q, \bar{Q}	-	43	65	ns
	High-Low Level	t_{pHL}		-	35	53	
Minimum Enable Pulse Width	t_w		-	40	60	ns	
Minimum Hold Time	t_{hold}		-	-	6	ns	
Minimum Set-up Time	t_{set-up}		-	25	44	ns	
Input Capacitance	C_{IN}		-	5	-	pF	

TC40H375P/F**SWITCHING TIME TEST CIRCUIT AND WAVEFORM**

TOSHIBA INTEGRATED CIRCUIT TECHNICAL DATA

TC40H375P/F

